
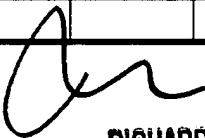
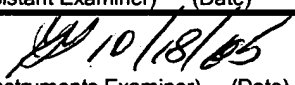


Issue Classification 	Application/Control No.		Applicant(s)/Patent under Reexamination	
	10/803,183		CHEN ET AL.	
	Examiner		Art Unit	
	Hien N. Nguyen		2824	

ISSUE CLASSIFICATION									
ORIGINAL					CROSS REFERENCE(S)				
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)			
365		185.17			365	185.29			
INTERNATIONAL CLASSIFICATION					257	314			
G	1	1	C	16/04					
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HIEN NGUYEN 10/20/05 (Assistant Examiner) (Date)					 10.17.05 RICHARD ELMS SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2800			Total Claims Allowed: 30	
 10/18/05 (Legal Instruments Examiner) (Date)								O.G. Print Claim(s) 1	

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant										<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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